

N-channel TrenchMOS standard level FET Rev. 2 — 16 May 2012

Product data sheet

1. **Product profile**

1.1 General description

Standard level N-channel MOSFET in a SOT404 package using TrenchMOS technology. This product has been designed and qualified to AEC Q101 standard for use in high performance automotive applications.

1.2 Features and benefits

- AEC Q101 compliant
- Repetitive avalanche rated

1.3 Applications

- 12 V Automotive systems
- Electric and electro-hydraulic power steering
- Motors, lamps and solenoid control

1.4 Quick reference data

- Suitable for thermally demanding environments due to 175 °C rating
- True standard level gate with VGS(th) rating of greater than 1V at 175 °C
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	60	V
I _D	drain current	V_{GS} = 10 V; T_{mb} = 25 °C; see <u>Figure 1</u>	<u>[1]</u> -	-	120	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	357	W
Static chara	acteristics					
R _{DSon}	drain-source on-state resistance	V _{GS} = 10 V; I _D = 25 A; T _j = 25 °C; see <u>Figure 11</u>	-	1.9	2.4	mΩ
Dynamic ch	naracteristics					
Q_{GD}	gate-drain charge	$I_D = 25 \text{ A}; V_{DS} = 48 \text{ V}; V_{GS} = 10 \text{ V};$ see <u>Figure 13</u> ; see <u>Figure 14</u>	-	45.5	-	nC

[1] Continuous current is limited by package.

Quick reference data

Table 1.



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2. Pinning information

Table 2.	Pinning	j information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		2
2	D	drain	mb	
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S
			SOT404 (D2PAK)	

3. Ordering information

Table 3. Ordering information						
Type number	Package					
	Name	Description	Version			
BUK762R4-60E	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)	SOT404			

4. Marking

Table 4. Marking codes	
Type number	Marking code
BUK762R4-60E	BUK762R4-60E

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5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	60	V
V _{DGR}	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	60	V
V _{GS}	gate-source voltage		-20	20	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u>	<u>[1]</u> _	120	А
		T_{mb} = 100 °C; V_{GS} = 10 V; see Figure 1	<u>[1]</u> _	120	А
I _{DM}	peak drain current	T _{mb} = 25 °C; pulsed; t _p ≤ 10 μs; see <u>Figure 4</u>	-	1047	A
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	357	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Source-drain	diode				
ls	source current	T _{mb} = 25 °C	<u>[1]</u> _	120	А
I _{SM}	peak source current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$	-	1047	А
Avalanche ru	Iggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$\label{eq:ID} \begin{array}{l} I_{D} = 120 \text{ A}; V_{sup} \leq 60 \text{ V}; \text{R}_{GS} = 50 \Omega; \\ V_{GS} = 60 \text{ V}; \text{T}_{j(\text{init})} = 25 ^{\circ}\text{C}; \text{ unclamped}; \\ \text{see } \overline{\text{Figure } 3} \end{array}$	<u>[2][3]</u> _	660	mJ

[1] Continuous current is limited by package.

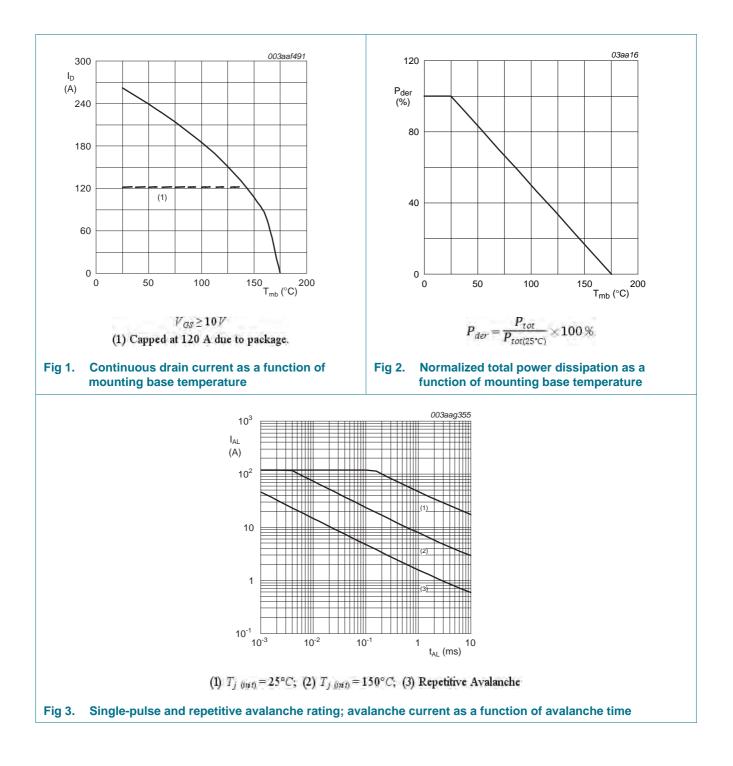
[2] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

[3] Refer to application note AN10273 for further information.

NXP Semiconductors

BUK762R4-60E

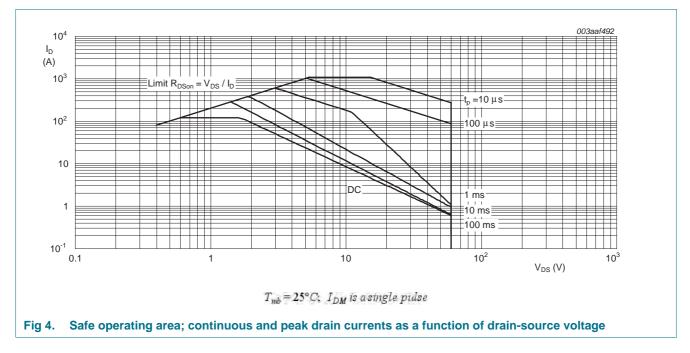
N-channel TrenchMOS standard level FET



NXP Semiconductors

BUK762R4-60E

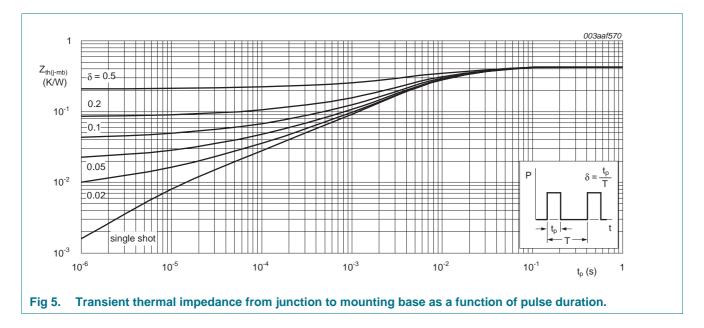
N-channel TrenchMOS standard level FET



6. Thermal characteristics

Table 6.Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{\text{th(j-mb)}}$	thermal resistance from junction to mounting base	see Figure 5	-	-	0.42	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	minimum footprint; mounted on a printed-circuit board	-	50	-	K/W

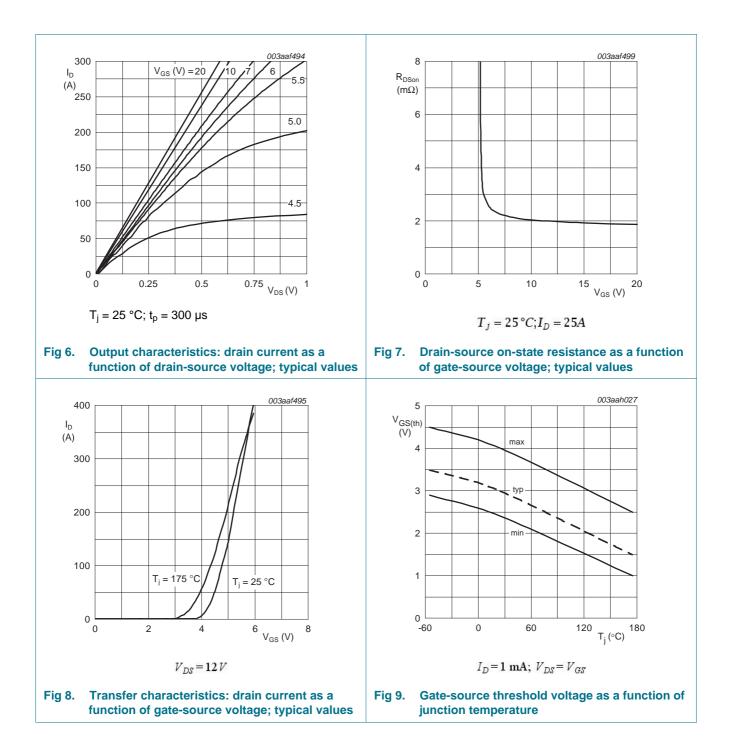


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7. Characteristics

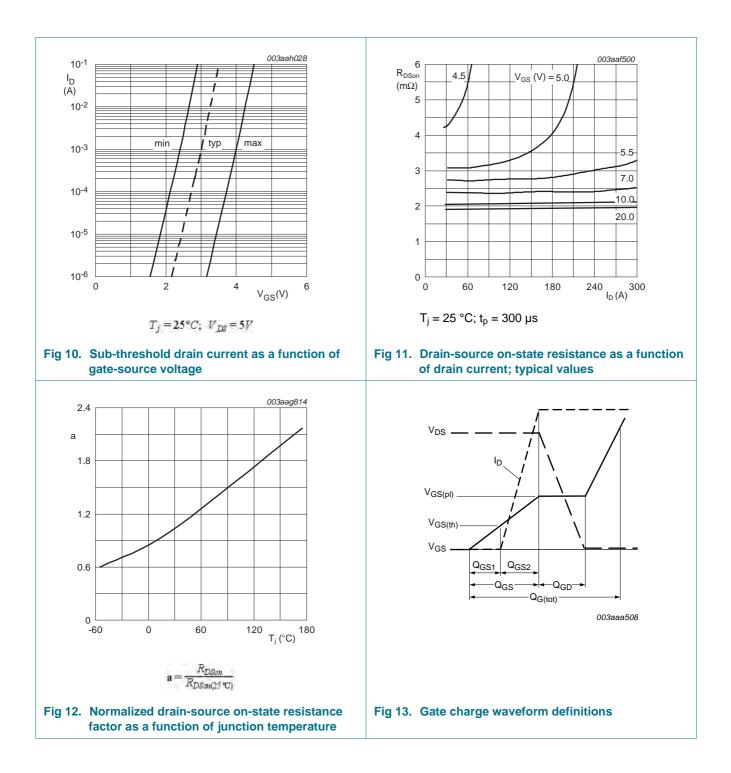
Static characteristics V(BR)DSS V(BR)DSS drain-source breakdown voltage I _D = 250 μ A; V _{GS} = 0 V; T _J = 25 °C 60 - V V(BR)DSS drain-source threshold voltage I _D = 250 μ A; V _{GS} = 0 V; T _J = 25 °C 54 - V VGS(th) gate-source threshold voltage I _D = 1 mA; V _{DS} = V _{GS} ; T _J = 25 °C; see Figure 9 2.4 3 4 V I _D = 1 mA; V _{DS} = V _{GS} ; T _J = 75 °C; see Figure 9 1 - - V I _{DSS} drain leakage current vos = 60 V; V _{GS} = 0 V; T _J = 25 °C - 0.15 1 μ A I _{DSS} drain-leakage current resistance V _{GS} = 0 V; V _{DS} = 0 V; T _J = 25 °C - 2 100 nA V _{GS} = 20 V; V _{DS} = 0 V; T _J = 25 °C - 2 100 nA V _{GS} = 20 V; V _{DS} = 0 V; T _J = 25 °C - 1.9 2.4 mΩ V _{GS} = 10V; T _J = 25 A; T _J = 25 °C; see Figure 11; see Figure 12 - 5.2 mΩ Dynamic characteristics - 1.9 2.4 MΩ Q _{GD} gate-source charge I _D	Table 7.	Characteristics					
$ \begin{array}{c c c c c c c } V_{GR(DSS} & drain-source breakdown voltage \\ breakdown voltage \\ \hline M_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ} C & 54 & - & - & V \\ \hline N_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^{\circ} C & 54 & - & - & V \\ \hline N_D = 1 \ m A; \ V_{DS} = V_{GS}; \ T_j = 25 \ ^{\circ} C; & 2.4 & 3 & 4 & V \\ \hline M_D = 1 \ m A; \ V_{DS} = V_{GS}; \ T_j = 175 \ ^{\circ} C; & 2.4 & 3 & 4 & V \\ \hline N_D = 1 \ m A; \ V_{DS} = V_{GS}; \ T_j = 175 \ ^{\circ} C; & 2.4 & 3 & 4 & V \\ \hline N_D = 1 \ m A; \ V_{DS} = V_{GS}; \ T_j = 175 \ ^{\circ} C; & 2.4 & 3 & 4 & V \\ \hline N_D = 1 \ m A; \ V_{DS} = V_{GS}; \ T_j = 175 \ ^{\circ} C; & 2 & 0 & 0.15 & 1 & \mu A \\ \hline N_D = 1 \ m A; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ} C; & 0.15 & 1 & \mu A \\ \hline V_{DS} = 60 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ} C; & 2 & 100 & nA \\ \hline V_{DS} = 60 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ} C; & 2 & 100 & nA \\ \hline V_{DS} = 20 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ} C; & 2 & 100 & nA \\ \hline V_{OS} = 20 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ} C; & 2 & 100 & nA \\ \hline V_{OS} = 10 \ V; \ I_D = 25 \ A; \ T_j = 25 \ ^{\circ} C; & 2 & 100 & nA \\ \hline V_{OS} = 10 \ V; \ I_D = 25 \ A; \ T_j = 25 \ ^{\circ} C; & 2 & 100 & nA \\ \hline V_{OS} = 10 \ V; \ I_D = 25 \ A; \ T_j = 25 \ ^{\circ} C; & 2 & 100 & nA \\ \hline V_{OS} = 10 \ V; \ I_D = 25 \ A; \ T_j = 25 \ ^{\circ} C; & - & 1.9 & 2.4 & m\Omega \\ \hline V_{OS} = 10 \ V; \ I_D = 25 \ A; \ T_j = 25 \ ^{\circ} C; & - & 1.9 & 2.4 & m\Omega \\ \hline V_{OS} = 10 \ V; \ I_D = 25 \ A; \ V_{DS} = 10 \ V; \\ \hline V_{OS} = 10 \ V; \ I_D = 25 \ A; \ V_{DS} = 10 \ V; \\ \hline V_{OS} = 0 \ V; \ V_{DS} = 25 \ V; \ F_1 \ MHZ; \\ \hline V_{OS} = 0 \ V; \ V_{DS} = 0 \ V; \ V_{DS} = 10 \ V; \\ \hline V_{OS} = 0 \ V; \ V_{DS} = 25 \ V; \ F_1 \ MHZ; \\ \hline C_{OS} \ I \ I \ I \ I \ I \ I \ I \ I \ I \ $	Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$ \begin{array}{c} \mbod{triangle}{\begin{tabular}{ c $	Static cha	racteristics					
$V_{GS(th)} = V_{GS} = 0, V_{GS} = 0, V_{T_1} = 25 \text{ °C}; \\ y_{es} = 0, V_{T_2} = 25 \text{ °C}; \\ y_{es} = 0, V_{T_2} = 25 \text{ °C}; \\ y_{es} = 0, V_{T_2} = 25 \text{ °C}; \\ y_{es} = 0, V_{T_2} = 25 \text{ °C}; \\ y_{es} = 0, V_{T_2} = 25 \text{ °C}; \\ y_{es} = 0, V_{T_2} = 25 \text{ °C}; \\ y_{es} = 0, V_{T_2} = 25 \text{ °C}; \\ y_{es} = 0, V_{T_2} = 25 \text{ °C}; \\ y_{es} = 0, V_{T_2} = 25 \text{ °C}; \\ y_{es} = 0, V_{T_2} = 25 \text{ °C}; \\ y_{es} = 0, V_{T_2} = 25 \text{ °C}; \\ y_{es} = 0, V_{T_2} = 25 \text{ °C}; \\ y_{es} = 0, V_{T_2} = 25 \text{ °C}; \\ y_{es} = 0, V_{T_2} = 25 \text{ °C}; \\ y_{es} = 0, V_{T_2} = 25 \text{ °C}; \\ y_{es} = 0, V_{T_2} = 25 \text{ °C}; \\ y_{es} = 0, V_{T_2} = 25 \text{ °C}; \\ y_{es} = 0, V_{T_2} = 25 \text{ °C}; \\ y_{es} = 20 \text{ °V}; V_{DS} = 0 \text{ °V}; T_1 = 175 \text{ °C}; \\ y_{es} = 10 \text{ °V}; t_0 = 25 \text{ A}; T_1 = 175 \text{ °C}; \\ y_{es} = 10 \text{ °V}; t_0 = 25 \text{ A}; T_1 = 175 \text{ °C}; \\ y_{es} = 10 \text{ °V}; t_0 = 25 \text{ A}; T_1 = 175 \text{ °C}; \\ y_{es} = 10 \text{ °V}; t_0 = 25 \text{ A}; T_1 = 175 \text{ °C}; \\ y_{es} = 10 \text{ °V}; t_0 = 25 \text{ A}; T_1 = 175 \text{ °C}; \\ y_{es} = 10 \text{ °V}; t_0 = 25 \text{ A}; T_1 = 175 \text{ °C}; \\ y_{es} = 10 \text{ °V}; t_0 = 25 \text{ A}; T_1 = 175 \text{ °C}; \\ y_{es} = 10 \text{ °V}; t_0 = 25 \text{ A}; T_1 = 175 \text{ °C}; \\ y_{es} = 10 \text{ °V}; t_0 = 25 \text{ A}; T_1 = 175 \text{ °C}; \\ y_{es} = 10 \text{ °V}; t_0 = 25 \text{ A}; T_1 = 175 \text{ °C}; \\ y_{es} = 10 \text{ °V}; t_0 = 25 \text{ A}; T_1 = 175 \text{ °C}; \\ y_{es} = 10 \text{ °V}; t_0 = 25 \text{ A}; y_{es} = 10 \text{ °V}; t_0 = 25 \text{ ~C}; \\ y_{es} = 10 \text{ °V}; t_0 = 25 \text{ ~C}; y_{es} = 10 \text{ °V}; t_0 = 110 \text{ °V}; t_0 = 1$	V _{(BR)DSS}		$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^\circ C$	60	-	-	V
$ \begin{tabular}{ c c c c c c c } \label{eq:product} $$ $$ $$ $$ $$ $$ $$ $$ $$ $$ $$ $$ $$$		breakdown voltage	$I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^\circ\text{C}$	54	-	-	V
	V _{GS(th)}	-		2.4	3	4	V
$\begin{tabular}{ c c c c c } \hline See Figure 9 & Conditional equation of the transfer of the transfer capacitance inductance inductan$,	1	-	-	V
$ \begin{array}{ c c c c c c c } & V_{DS} = 60 \ V; \ V_{GS} = 0 \ V; \ V_{IJ} = 175 \ ^{\circ}C & - & 2 & 100 & nA \\ \hline V_{GS} = 20 \ V; \ V_{DS} = 0 \ V; \ V_{IJ} = 25 \ ^{\circ}C & - & 2 & 100 & nA \\ \hline V_{GS} = -20 \ V; \ V_{DS} = 0 \ V; \ V_{IJ} = 25 \ ^{\circ}C & - & 2 & 100 & nA \\ \hline V_{GS} = -20 \ V; \ V_{DS} = 0 \ V; \ V_{IJ} = 25 \ ^{\circ}C & - & 2 & 100 & nA \\ \hline V_{GS} = -20 \ V; \ V_{DS} = 0 \ V; \ V_{IJ} = 25 \ ^{\circ}C & - & 2 & 100 & nA \\ \hline V_{GS} = 10 \ V; \ V_{DS} = 25 \ A; \ T_{J} = 25 \ ^{\circ}C & - & 5.2 & m\Omega \\ \hline V_{GS} = 0 \ V; \ V_{DS} = 0 \ V; \ V_{DS} = 25 \ A; \ T_{J} = 175 \ ^{\circ}C ; & - & 5.2 & m\Omega \\ \hline V_{GS} = 0 \ V; \ V_{DS} = 25 \ A; \ T_{J} = 175 \ ^{\circ}C ; & - & 5.2 & m\Omega \\ \hline V_{GS} = 0 \ V; \ V_{DS} = 25 \ A; \ V_{DS} = 10 \ V; & - & 5.2 & m\Omega \\ \hline Dynamic \ characteristics & & & & & & & & & & \\ \hline Dynamic \ characteristics & & & & & & & & & & & & & & & & & & &$,	-	-	4.5	V
	I _{DSS}	drain leakage current	$V_{DS} = 60 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.15	1	μA
$ \frac{V_{GS} = -20 \ V; \ V_{DS} = 0 \ V; \ T_{J} = 25 \ ^{\circ}C & - & 2 & 100 nA \\ \ R_{DSon} & drain-source on-state resistance & V_{GS} = 10 \ V; \ I_{D} = 25 \ A; \ T_{J} = 25 \ ^{\circ}C; & - & 1.9 & 2.4 & m\Omega \\ \hline ee \ Figure 11 & V_{GS} = 10 \ V; \ I_{D} = 25 \ A; \ T_{J} = 175 \ ^{\circ}C; & - & - & 5.2 & m\Omega \\ \hline ese \ Figure 11 & v_{GS} = 10 \ V; \ I_{D} = 25 \ A; \ T_{J} = 175 \ ^{\circ}C; & - & - & 5.2 & m\Omega \\ \hline Dynamic characteristics & & & & & & & & & & & & & & & & & & &$			$V_{DS} = 60 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μA
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	I _{GSS}	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
$ \begin{array}{ c c c c c } resistance & see \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \$			$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	2	100	nA
see Figure 11; see Figure 12 Dynamic characteristics $Q_{G(tot)}$ total gate charge $I_D = 25 \text{ Å; V_{DS} = 48 \text{ V; V}_{GS} = 10 \text{ V;}$ see Figure 13; see Figure 14 - 158 - nC Q_{GD} gate-drain charge $V_{SS} = 0 \text{ V; V_{DS} = 25 \text{ V; } f = 1 \text{ MHz;}$ - 9380 11180 pF C_{iss} input capacitance $V_{GS} = 0 \text{ V; V_{DS} = 25 \text{ V; } f = 1 \text{ MHz;}$ - 9380 11180 pF C_{oss} output capacitance $V_{GS} = 0 \text{ V; V_{DS} = 25 \text{ V; } f = 1 \text{ MHz;}$ - 9380 11180 pF C_{oss} output capacitance $V_{DS} = 45 \text{ V; } \text{ R}_{L} = 1.8 \Omega; \text{ V}_{GS} = 10 \text{ V;}$ - 642 880 pF $t_{q(on)}$ turn-on delay time $V_{DS} = 45 \text{ V; } \text{ R}_{L} = 1.8 \Omega; \text{ V}_{GS} = 10 \text{ V;}$ - 36 - ns $t_{q(onf)}$ turn-off delay time V_{DS} = 45 \text{ V; } \text{ R}_{L} = 1.8 \Omega; \text{ V}_{GS} = 10 \text{ V;} - 36 - ns $t_{q(onf)}$ turn-off delay time from upper edge of mounting base to centre of die; T_{j} = 25 \text{ °C} - <t< td=""><td>R_{DSon}</td><td></td><td></td><td>-</td><td>1.9</td><td>2.4</td><td>mΩ</td></t<>	R _{DSon}			-	1.9	2.4	mΩ
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$				-	-	5.2	mΩ
Aug see Figure 13; see Figure 14 - 35.3 - nC Q_{GD} gate-drain charge - 45.5 - nC C_{iss} input capacitance $V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz;$ - 9380 11180 pF C_{oss} output capacitance $T_j = 25 {}^\circ$ C; see Figure 15 - 1066 1280 pF C_{rss} reverse transfer capacitance V_{DS} = 45 V; R_L = 1.8 \Omega; V_{GS} = 10 V; - 36 - ns $t_{d(on)}$ turn-on delay time $V_{DS} = 45 V; R_L = 1.8 \Omega; V_{GS} = 10 V;$ - 36 - ns $t_{d(off)}$ turn-off delay time V_{DS} = 45 V; R_L = 1.8 \Omega; V_{GS} = 10 V; - 36 - ns $t_{d(off)}$ turn-off delay time V_{DS} = 5 \Omega - ns - 130 - ns L_D internal drain inductance from upper edge of mounting base to centre of die; $T_j = 25 {}^\circ$ C - NL - NL Source-drain diode - V_SD source-drain voltage I_S = 25 A; V_{GS} = 0 V; T_j = 25 {}^\circC; see Figure 16 - 0.77	Dynamic	characteristics					
large gate source of large - 45.5 - nC Q_{GD} gate-drain charge - 45.5 - nC C_{iss} input capacitance $V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz;$ - 9380 11180 pF C_{oss} output capacitance $V_{GS} = 0 V; V_{DS} = 25 °C;$ see Figure 15 - 1066 1280 pF C_{rss} reverse transfer capacitance - 642 880 pF $t_{d(on)}$ turn-on delay time $V_{DS} = 45 V; R_L = 1.8 \Omega; V_{GS} = 10 V;$ - 36 - ns $t_{d(off)}$ turn-off delay time V_{DS} = 45 V; R_L = 1.8 \Omega; V_{GS} = 10 V; - 36 - ns $t_d(off)$ turn-off delay time V_{DS} = 45 V; R_L = 1.8 \Omega; V_{GS} = 10 V; - 36 - ns t_p fall time V_{DS} = 5 \Omega - ns - 1130 - ns L_D internal drain from upper edge of mounting base to centre of die; $T_j = 25 °C$ - 7.5 - nH L_S internal source measured from source lead to sou	Q _{G(tot)}	total gate charge		-	158	-	nC
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Q_{GS}	gate-source charge	see Figure 13; see Figure 14	-	35.3	-	nC
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Q_{GD}	gate-drain charge		-	45.5	-	nC
C_{rss} reverse transfer capacitance-642880pF $t_{d(on)}$ turn-on delay time $V_{DS} = 45 \text{ V}; \text{ R}_L = 1.8 \Omega; \text{ V}_{GS} = 10 \text{ V};$ r rise time-36-ns t_r rise time $R_{G(ext)} = 5 \Omega$ -50-ns $t_{d(off)}$ turn-off delay time-130-ns $t_{d(off)}$ turn-off delay time-71-ns t_f fall time-71-nsL_Dinternal drain inductancefrom upper edge of mounting base to centre of die; $T_j = 25 \text{ °C}$ -7.5-nHL_Sinternal source inductancemeasured from source lead to source bond pad; $T_j = 25 \text{ °C}$ -0.771.2VSource-drain diodeV $S = 25 \text{ A}; \text{ V}_{GS} = 0 \text{ V}; T_j = 25 \text{ °C};$ -0.771.2V t_{rr} reverse recovery time $I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A}/\mus; \text{ V}_{GS} = 0 \text{ V};$ -54-ns	C _{iss}	input capacitance		-	9380	11180	pF
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	C _{oss}	output capacitance	$T_j = 25 \text{ °C}; \text{ see } Figure 15$	-	1066	1280	pF
t_r rise time $R_{G(ext)} = 5 \Omega$ - 50 -ns $t_{d(off)}$ turn-off delay time- 130 -ns t_r fall time- 71 -ns L_D internal drain inductancefrom upper edge of mounting base to centre of die; $T_j = 25 ^{\circ}C$ - 2.5 -nH L_S internal source inductancemeasured from source lead to source bond pad; $T_j = 25 ^{\circ}C$ - 7.5 -nHSource-drain diode V_{SD} source-drain voltage $I_S = 25 ^{\circ}A; V_{GS} = 0 ^{\circ}V; T_j = 25 ^{\circ}C;$ see Figure 16- 0.77 1.2 V t_{rr} reverse recovery time $I_S = 20 ^{\circ}A; dI_S/dt = -100 ^{\circ}A \mu s; V_{GS} = 0 ^{\circ}V;$ - 54 -ns	C _{rss}			-	642	880	pF
trHoe timeHoe timeHoe timetd(off)turn-off delay time-130-nstrfall time-71-nsLDinternal drain inductancefrom upper edge of mounting base to centre of die; $T_j = 25 \ ^{\circ}C$ -2.5-nHLSinternal source inductancemeasured from source lead to source bond pad; $T_j = 25 \ ^{\circ}C$ -7.5-nHSource-drain diode-Source-drain voltageI_S = 25 A; V_{GS} = 0 V; $T_j = 25 \ ^{\circ}C$; see Figure 16-0.771.2Vtrrreverse recovery timeI_S = 20 A; dls/dt = -100 A/µs; V_{GS} = 0 V; $V = -25 \ ^{\circ}V$ -54-ns	t _{d(on)}	turn-on delay time		-	36	-	ns
t_f fall time-71-ns L_D internal drain inductancefrom upper edge of mounting base to centre of die; $T_j = 25 \ ^\circ$ C-2.5-nH L_S internal source inductancemeasured from source lead to source bond pad; $T_j = 25 \ ^\circ$ C-7.5-nHSource-drain diode V_{SD} source-drain voltage $I_S = 25 \ A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^\circ$ C; see Figure 16-0.771.2V t_{rr} reverse recovery time $I_S = 20 \ A; \ dI_S/dt = -100 \ A/\mu s; \ V_{GS} = 0 \ V; \54-ns$	t _r	rise time	$R_{G(ext)} = 5 \Omega$	-	50	-	ns
L_D internal drain inductancefrom upper edge of mounting base to centre of die; $T_j = 25 \ ^{\circ}C$ - 2.5 - nH L_S internal source inductancemeasured from source lead to source bond pad; $T_j = 25 \ ^{\circ}C$ - 7.5 - nH Source-drain diode V_{SD} source-drain voltage $I_S = 25 \ A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C;$ see Figure 16- 0.77 1.2 V t_{rr} reverse recovery time $I_S = 20 \ A; \ dI_S/dt = -100 \ A/\mu s; \ V_{GS} = 0 \ V;$ - 54 -ns	t _{d(off)}	turn-off delay time		-	130	-	ns
inductancecentre of die; $T_j = 25 \text{ °C}$ L_Sinternal source inductancemeasured from source lead to source bond pad; $T_j = 25 \text{ °C}$ -7.5-nHSource-drain diodeV_{SD}source-drain voltageI_S = 25 A; V_{GS} = 0 V; T_j = 25 °C; see Figure 16-0.771.2Vtrrreverse recovery timeI_S = 20 A; dI_S/dt = -100 A/µs; V_{GS} = 0 V; 54-ns	t _f	fall time		-	71	-	ns
inductancebond pad; $T_j = 25 \text{ °C}$ Source-drain diode V_{SD} source-drain voltage $I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C};$ -0.771.2V t_{rr} reverse recovery time $I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A}/\mu\text{s}; V_{GS} = 0 \text{ V};$ -54-ns	L _D			-	2.5	-	nH
V_{SD} source-drain voltage $I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C};$ see Figure 16-0.771.2V t_{rr} reverse recovery time $I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A}/\mu s; V_{GS} = 0 \text{ V};$ -54-ns	L _S			-	7.5	-	nH
see Figure 16 t_{rr} reverse recovery time $I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A}/\mu s; V_{GS} = 0 \text{ V};$ - 54 - ns	Source-di	ain diode					
V 25 V	V_{SD}	source-drain voltage		-	0.77	1.2	V
Q_r recovered charge $V_{DS} = 25 V$ - 89 - nC	t _{rr}	reverse recovery time	$I_{S} = 20 \text{ A}; \text{dI}_{S}/\text{dt} = -100 \text{ A}/\mu\text{s}; \text{V}_{GS} = 0 \text{ V};$	-	54	-	ns
	Qr	recovered charge	$V_{DS} = 25 V$	-	89	-	nC

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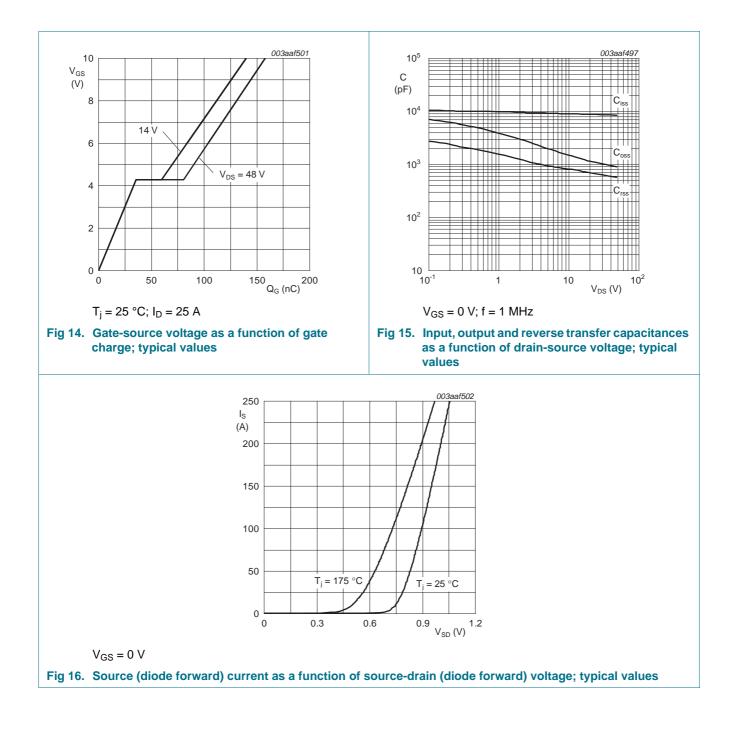


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8. Package outline

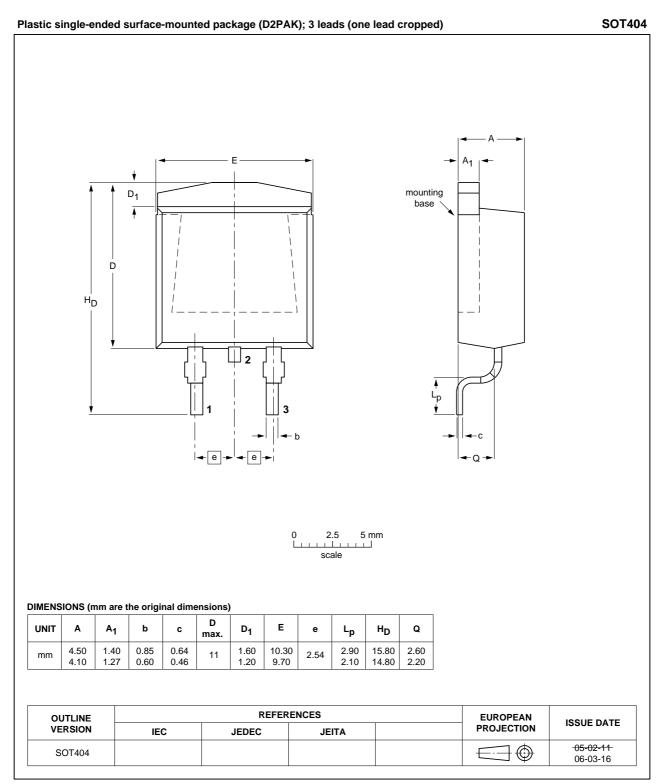


Fig 17. Package outline SOT404 (D2PAK)

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9. Revision history

Table 8.Revision	history			
Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK762R4-60E v.2	20120516	Product data sheet	-	BUK762R4-60E v.1
Modifications:	 Status change 	d from objective to product.		
	 Various chang 	es to content.		
BUK762R4-60E v.1	20120404	Objective data sheet	-	-

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10. Legal information

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Document status[1] [2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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[2] The term 'short data sheet' is explained in section "Definitions".

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